

12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN# 20111117003B Qualification of TIEM (Melaka, MLA) as an Additional Assembly and Test Site option for select devices in the DCQ package Change Notification

Dear Customer:

The purpose of this B version of the PCN is to retract TPS7A4501DCQR/T device highlighted in yellow in the "Product Affected" section of this document.

Severe flooding in Thailand has temporarily disrupted production at some of TI's suppliers, including the sub-contractor Hana Thailand (HNT).

TI is being updated on the situation daily by our production and logistics partners and has taken several actions to mitigate the potential impact to supply, including identifying and qualifying alternative sources.

This is an announcement for the transfer of product to alternate assembly and test sites. To minimize the supply disruption to TI's customer base, we are moving quickly to shift production for the package families identified within this PCN.

While TI has made every attempt to ensure this PCN is inclusive of all needed transfers based on our best current knowledge, this list is subject to change. TI will send updates if changes are identified. In addition, PCNs associated with the related capacity transfers could be accelerated if they enable more efficient usage of the defined alternate sites.

In addition to the prior mentioned transfer strategy that incorporates package family quals and alternate site selection based on each site's current qualification status, TI intends to reduce customer risk by performing additional device yield/bin analysis prior to production deliveries.

TI is committed to delivering quality products while also working with our customers to minimize supply gaps.

Please find the details of this strategy on the following pages. TI requests you acknowledge receipt of this notification within **21** days of the date of this notification. In order to minimize supply delays, TI has already initiated production at the alternate sites with material availability and shipments beginning as early as January 2012.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN ww admin team@list.ti.com).

Sincerely,

PCN Team SC Business Services

20111117003B Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

TPS7A4501DCQT

Technical details of this Product Change follow on the next page(s).

PCN Number:			2	20111117002P					DCN Data: Mar 29 2017			
Qualification				20111117003B PCN Date: Mar 28, 2017 of TIEM (Melaka, MLA) as an Additional Assembly and Test Site option for								
				in the DCQ package								
					<u>ager</u>	J	Dept	: (Qual	lit	y Services	
Change Type:									•			
\boxtimes	Assemb	ly Site		☐ Assembly Process ☐			Assembly Materials					
	Design					Electric	al Specifi	ication	1]	Mechanical Specification
\boxtimes	Test Sit]	Packing	J/Shippin	g/Lab	eling]	Test Process
	Wafer E				<u> </u>	Wafer E	Bump Ma	terial				Wafer Bump Process
	Wafer F	ab Site		Wafer		Wafer F	ab Materials				Wafer Fab Process	
							PCN D	etail	S			
Descri	iption of	Chang	je:									
The purpose of Version B is to retract TPS7A4501DCQR/T device from this notification. This will continue to be sourced from HNT. The device affected is highlighted in yellow in the Product Affected Section and with a strikethrough . Qualification of TIEM (Melaka, MLA) as an Additional Assembly and Test Site option for select												
		OCQ pac	kage.	Se	ее	table be	elow for a	asseml	oly comp	aris	80	n/differences between current
and ne	w sites:											
				ırrent: HNT			New:TIEM-AT					
	Compour		400159				080598					
	Compound wire diame		1.0 mil	50179			096890 1.0 mil					
Boria (wii e diairi			.0 mils			1.3 mils					
			1.5 mils			1.5 mils						
		2.0 mils			2	2.0 mils						
Lead Frame NiPdA		<u> NiPdAu</u>	dAu, Cu		IV	Matte Sn						
Upon expiration of this PCN, TI will combine lead free solutions in a single <u>standard part number</u> , for example; <u>TPS79430DCQ</u> – can ship with both Matte Sn and NiPdAu.												
Examp		custome	er orde	r fo	or :	75 units	of TPS7	9430D	CQ with	25	u	nits SPQ (Standard Pack
Quantity per Tube).												
TI can satisfy the above order in one of the following ways. 2. T. base of NID IAs Golden.						ays.						
I. 3 Tubes of NiPdAu finish. II. 3 Tubes of Matte Sn finish												
				3 Tubes of Matte Sn finish 2 Tubes of Matte Sn and 1 tube of NiPdAu finish.							ı finish	
IV.				2 Tubes of Matte Sir and 1 tube of MirdAu 2 Tubes of NiPdAu and 1 tube of Matte Sn								
Reason for Change:												
Continuity of Supply. Introduce alternate sites due to the temporary closure of Hana Thailand.												
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):												
None.												
Changes to product identification resulting from this PCN:												
Assembly Site												
HNT		Assembly Site Origin (22L		n (22L)	ASO: HNT							
TIEM Assembly Site Original												

Sample product shipping label to show code location only - not actual product label



(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483\$I2 (P) (2P) REV: (V) 0033317

PTEM: 5A (L)TO: 1750

(2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

There will be no change in topside symbolization (shown below).

Device Marking:

R102G50 YMLLLLS LLLL O

YM = YEAR MONTH DATE CODE

LLLL = ASSEMBLY LOT CODE

S = ASSEMBLY SITE CODE (Varies by Assembly Site)

O = PIN 1 INDICATOR

O - PIN 1 (MARKED)

Products Affected:

HPA00162DCQ	TL1963A-33DCQR	TPS73618DCQR	TPS79433DCQR
HPA00400DCQR	TL1963A-33DCQT	TPS73625DCQ	TPS79501DCQ
HPA00401DCQR	TL1963ADCQR	TPS73625DCQR	TPS79501DCQR
HPA00501DCQR	TL1963ADCQT	TPS73630DCQ	TPS79516DCQ
HPA00524DCQR	TPS72501DCQ	TPS73630DCQR	TPS79516DCQR
HPA00610DCQR	TPS72501DCQR	TPS73633DCQ	TPS79518DCQ
HPA01087DCQR	TPS72515DCQ	TPS73633DCQR	TPS79518DCQR
REG102GA-2.5	TPS72515DCQR	TPS73701DCQ	TPS79525DCQ
REG102GA-2.85	TPS72516DCQ	TPS73701DCQR	TPS79525DCQR
REG102GA-3	TPS72516DCQR	TPS73718DCQ	TPS79530DCQ
REG102GA-3.3	TPS72518DCQ	TPS73718DCQR	TPS79530DCQR
REG102GA-3.3/2K5	TPS72518DCQR	TPS73725DCQ	TPS79533DCQ
REG102GA-5	TPS72525DCQ	TPS73725DCQR	TPS79533DCQR
REG102GA-5/2K5	TPS72525DCQR	TPS73733DCQ	TPS79601DCQ
REG102GA-A	TPS726126DCQ	TPS73733DCQR	TPS79601DCQR
REG102GA-A/2K5	TPS726126DCQR	TPS73734DCQ	TPS79618DCQ
REG103GA-2.5	TPS72615DCQ	TPS73734DCQR	TPS79618DCQR
REG103GA-2.5/2K5	TPS72615DCQR	TPS73801DCQR	TPS79625DCQ
REG103GA-2.7	TPS72616DCQ	TPS78601DCQ	TPS79625DCQR
REG103GA-3	TPS72616DCQR	TPS78601DCQR	TPS79628DCQ
REG103GA-3.3	TPS72618DCQ	TPS78618DCQ	TPS79628DCQR
REG103GA-3.3/2K5	TPS72618DCQR	TPS78618DCQR	TPS79630DCQ
REG103GA-5	TPS72625DCQ	TPS78625DCQ	TPS79630DCQR
REG103GA-5/2K5	TPS72625DCQR	TPS78625DCQR	TPS79633DCQ
REG103GA-A	TPS73201DCQ	TPS78628DCQR	TPS79633DCQR
REG103GA-A/2K5	TPS73201DCQR	TPS78630DCQ	TPS79650DCQ
REG104GA-2.5	TPS73215DCQ	TPS78630DCQR	TPS79650DCQR

REG104GA-2.5/2K5 T		3215DCQR	TPS78	633DCQ	TPS7A4501DCQR			
REG104GA-3 T		3218DCQ	TPS78	633DCQR	TPS7A4501DCQT			
		3218DCQR	TPS78	650DCQ	TPS7A4515DCQR			
		3225DCQ	TPS78	650DCQR	TPS7A4515DCQT			
REG104GA-5 T	PS7	3225DCQR	TPS79	401DCQ	TPS7A4518DCQR		QR	
REG104GA-5/2K5 T	PS7	3230DCQR	TPS79	401DCQR	TPS7A4518DCQT			
REG104GA-A T	PS7	3233DCQ	TPS79	418DCQ	TPS7A4525DCQR		QR	
REG104GA-A/2K5 T	PS7	3233DCQR	TPS79	418DCQR	TPS7A4525DCQ		:QT	
SN0804036DCQR T	PS7	3250DCQ	TPS79	425DCQ	TPS7A4533DC0		QR	
TL1963A-15DCQR T	PS7	3250DCQR	TPS79	425DCQR	TPS7A4533DCQ		:QT	
TL1963A-15DCQT T	PS7	3601DCQ	TPS79	428DCQ	TPS7A6701DCQR		QR	
TL1963A-18DCQR T	PS7	3601DCQR	TPS79	428DCQR	TPS7A6801DCQR		QR	
TL1963A-18DCQT T	PS7	3615DCQ	TPS79	430DCQ				
TL1963A-25DCQR T	PS7	3615DCQR	TPS79	430DCQR				
TL1963A-25DCQT T	PS7	3618DCQ	TPS79	433DCQ				
			ication					
This qualification has been specified to a that the proposed of							cation data	
validates that the proposed of Qualification Schedule :			12/2011		End: End of 01/2012)
				MSL = LEVEL2-2			31 0 17 20 12	
Assembly Si		TIEM-Melaka		Mold Compound: 096890				
# Pins-Designator, Fami	ly:	6-DCQ, SOT223		Mount Compound: 0805				
Lead Frame (Finish, Base	_	Matte SN, Cu		Bond Wire: 1.5 Mil D			Dia., Au	
Passivatio								
Qualification:	<u> </u>	Test Results						Ciao
Reliability Test	C	Conditions					Sample (PASS/F	
Preconditioning		(per the appropriate pkg level)					154/0	
Electrical Characterization		Full Temperature					15/0	
High Temp. Storage Bake		170 C / 420 Hrs (3xReflow))
**Unbiased HAST		130C/85%RH (96Hrs))
**T/C -65C/150C		-65C/+150C (500 Cycles) (per mechanical drawing))
Physical Dimensions Bond Strength		76 ball bonds, min. 3 units)
Bond Pull	I	Indicate Downbonds vs. lead finger results. 76 Wire, 3)
Die Shear	-	units min)
Manufacturability	((per mfg. Site specification)						;
X-ray		(top side only)						
Moisture Sensitivity		(level 2 @ 260C +5/-0C)					12/0)
**Preconditioning: L2C -260C								
	nicle 2: TPS737	701DCQ						
Assembly S		TIEM-Melaka		Mold Compound		096890		
# Pins-Designator, Fam						Dia A		
Lead Fini Passivatio						1.3 Mils	טומ., AU	
1 033170111	J. I.	12101 011						

Qualification: Plan	☐ Test Results						
Doliability Toot	Conditions		Sample Size (PASS/FAIL)				
Reliability Test	Conditions		Lot # 1	Lot # 2			
Preconditioning	(per the approp	riate pkg level)	231/0	77/0			
Electrical Characterization.	Full Temperatur	e(PDS)	15/0	-			
High Temp. Storage Bake	170 C / 420 Hrs	(3xReflow)	77/0 -				
**Biased HAST	130C/85%RH (9	96 Hrs)	77/0	77/0			
**Unbiased HAST	130C/85%RH (9	96Hrs)	77/0	-			
**T/C -65C/150C	-65C/+150C (5	600 Cycles)	77/0 -				
Post Wafer Saw Inspection	30 die/wafer, 5	separate locations	30/0	30/0			
Physical Dimensions	(per mechanica	drawing)	5/0	5/0			
Bond Strength	76 ball bonds, n	nin. 3 units	76/0	76/0			
Bond Pull	Indicate Down k results. 76 Wire	oonds vs. lead finger , 3 units min	76/0	76/0			
Die Shear	-		10/0	10/0			
Manufacturability (Assembly)	(per mfg. Site s	pecification)	Pass	Pass			
X-ray	(top side only)	,	5/0	-			
Moisture Sensitivity	(level 2 @ 260C	C +5/-0C)	12/0	_			
**Preconditioning: L2C -2600		,					
Qual Vehicle 3: TPS7A4501DCQ MSL = LEVEL2-260C							
Assembly Site:	TIEM-Melaka	Mold Compound:					
# Pins-Designator, Family:	6-DCQ, SOT223	Mount Compound:					
Lead Frame (Finish, Base):	Matte SN, Cu	Bond Wire:	2.0 Mils Dia.	, Au			
Passivation:	10KACN						
Qualification: Plan Test Results							
Reliability Test	Conditions		Sample Size (F	PASS/FAIL)			
Preconditioning	(per the approp	riate pkg level)	154/0				
Electrical Characterization	Full Temperatur	e	15/0				
High Temp. Storage Bake	150C (1000 Hrs) (3xReflow)	77/0				
**Unbiased HAST	130C/85%RH (9	96Hrs)	77/0				
**T/C -65C/150C	-65C/+150C (5	00 Cycles)	77/0				
Solderability	Steam age, 8 ho	ours	22/0				
Lead Pull	# of leads to de	struction, min. 3 units	22/0				
Lead Fatigue	# of leads, min.	3 units	22/0				
Lead Finish Adhesion	# of leads, min.	3 units	15/0				
Physical Dimensions	(per mechanica	l drawing)	5/0				
Flammability	Method A - UL9	4-0	5/0				
Die Shear	-		10/0				
Manufacturability	(per mfg. Site s	pecification)	1/0				
Salt Atmosphere	24 Hrs		22/0				
X-ray	(top side only)		5/0				
Moisture Sensitivity	(level 2 @ 2600	C +5/-0C)	12/0				
**Preconditioning: L2C -2600	**Preconditioning: L2C -260C						

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail		
USA	PCNAmericasContact@list.ti.com		
Europe	PCNEuropeContact@list.ti.com		
Asia Pacific	PCNAsiaContact@list.ti.com		
Japan	PCNJapanContact@list.ti.com		